

HIGH-SPEED SILICON DIODES



Planar epitaxial diodes intended for general purpose applications.

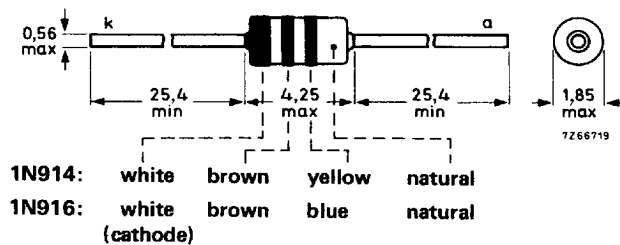
QUICK REFERENCE DATA

Continuous reverse voltage	V_R	max.	75 V
Repetitive peak reverse voltage	V_{RRM}	max.	100 V
Repetitive peak forward current	I_{FRM}	max.	225 mA
Forward voltage $I_F = 10$ mA	V_F	<	1 V
Reverse recovery time when switched from $I_F = 10$ mA to $I_R = 60$ mA; $R_L = 100 \Omega$; measured at $I_R = 1$ mA	t_{rr}	<	4 ns

MECHANICAL DATA

Dimensions in mm

Fig. 1 SOD-27 (DO-35).



Diodes may be either type-branded or colour-coded.

RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC 134)

Continuous reverse voltage	V_R	max.	75 V
Repetitive peak reverse voltage	V_{RRM}	max.	100 V
Average rectified forward current (averaged over any 20 ms period)			
$T_{amb} = 25\text{ }^{\circ}\text{C}$	$I_F(AV)$	max.	75 mA
$T_{amb} = 150\text{ }^{\circ}\text{C}$	$I_F(AV)$	max.	10 mA
Forward current (d.c.)	I_F	max.	75 mA
Repetitive peak forward current	I_{FRM}	max.	225 mA
Non-repetitive peak forward current ($t = 1\text{ s}$)	I_{FSM}	max.	500 mA
Total power dissipation	P_{tot}	max.	250 mW
Storage temperature	T_{stg}		$-65\text{ to }+200\text{ }^{\circ}\text{C}$
Operating ambient temperature	T_{amb}		$-65\text{ to }+175\text{ }^{\circ}\text{C}$

CHARACTERISTICS

 $T_j = 25\text{ }^{\circ}\text{C}$ unless otherwise specified

Forward voltages

 $I_F = 10\text{ mA}$ $V_F < 1\text{ V}$

Reverse avalanche breakdown voltage

 $I_R = 100\text{ }\mu\text{A}$ $V_{(BR)R} > 100\text{ V}$

Reverse currents

 $V_R = 20\text{ V}$ $I_R < 25\text{ nA}$ $V_R = 75\text{ V}$ $I_R < 5\text{ }\mu\text{A}$ $V_R = 20\text{ V}; T_j = 150\text{ }^{\circ}\text{C}$ $I_R < 50\text{ }\mu\text{A}$

Diode capacitance

 $V_R = 0; f = 1\text{ MHz}$

1N914

 $C_d < 4\text{ pF}$

1N916

 $C_d < 2\text{ pF}$

Forward recovery voltage

when switched to $I_F = 50\text{ mA}; t_r = 20\text{ ns}$ $V_{fr} < 2,5\text{ V}$

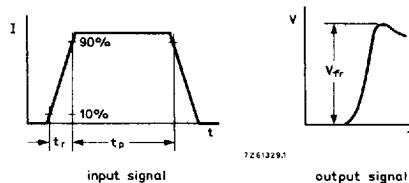
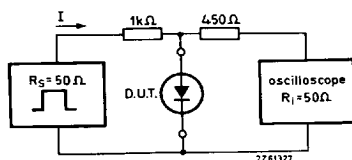


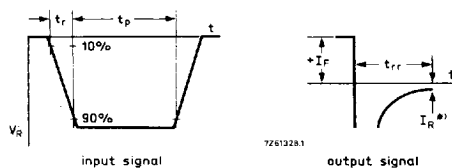
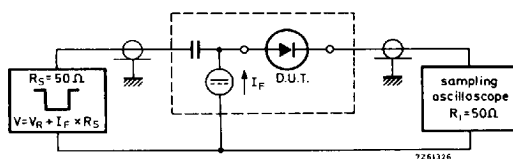
Fig. 2 Test circuit and waveforms forward recovery voltage. Input signal: Rise time of the forward pulse, $t_r = 20$ ns; forward current pulse duration, $t_p = 120$ ns; duty factor, $d = 0,01$. Oscilloscope rise time, $t_r = 0,35$ ns. Circuit capacitance < 1 pF (oscilloscope input capacitance and parasitic capacitance).

Reverse recovery time when switched from

$I_F = 10$ mA to $I_R = 10$ mA, $R_L = 100 \Omega$, measured at $I_R = 1$ mA

$I_F = 10$ mA to $I_R = 60$ mA, $R_L = 100 \Omega$, measured at $I_R = 1$ mA

	1N914	1N916
t_{rr}	8	— ns
t_{rr}	4	4 ns



* $I_R = 1$ mA

Fig. 3 Test circuit and waveform reverse recovery time. Input signal: Rise time of the reverse pulse, $t_r = 0,6$ ns; reverse pulse duration, $t_p = 100$ ns; duty factor, $d = 0,05$. Oscilloscope rise time, $t_r = 0,35$ ns. Circuit capacitance < 1 pF (oscilloscope input capacitance + parasitic capacitance).

Rectifying efficiency

$f = 100$ MHz; $V_{i(rms)} = 2$ V

$\eta > 45 \%$

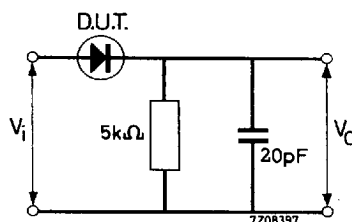


Fig. 4 Test circuit. $\eta = \frac{V_O}{V_{i(rms)}\sqrt{2}}$